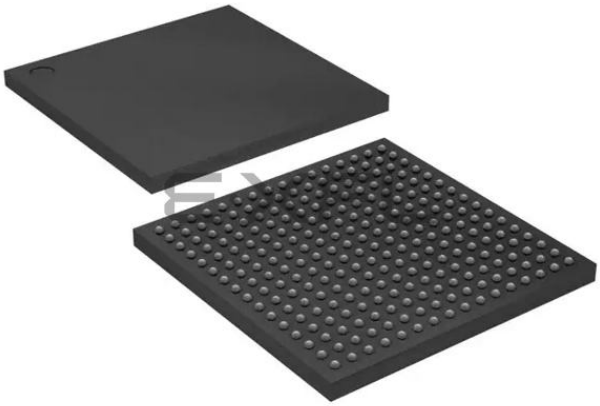


Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	903
Number of Logic Elements/Cells	14448
Total RAM Bits	239616
Number of I/O	152
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2c15af256c8n

Chapter 10. Selectable I/O Standards in Cyclone II Devices
Revised: *February 2008*
Part number: *CII51010-2.4*

Chapter 11. High-Speed Differential Interfaces in Cyclone II Devices
Revised: *February 2007*
Part number: *CII51011-2.2*

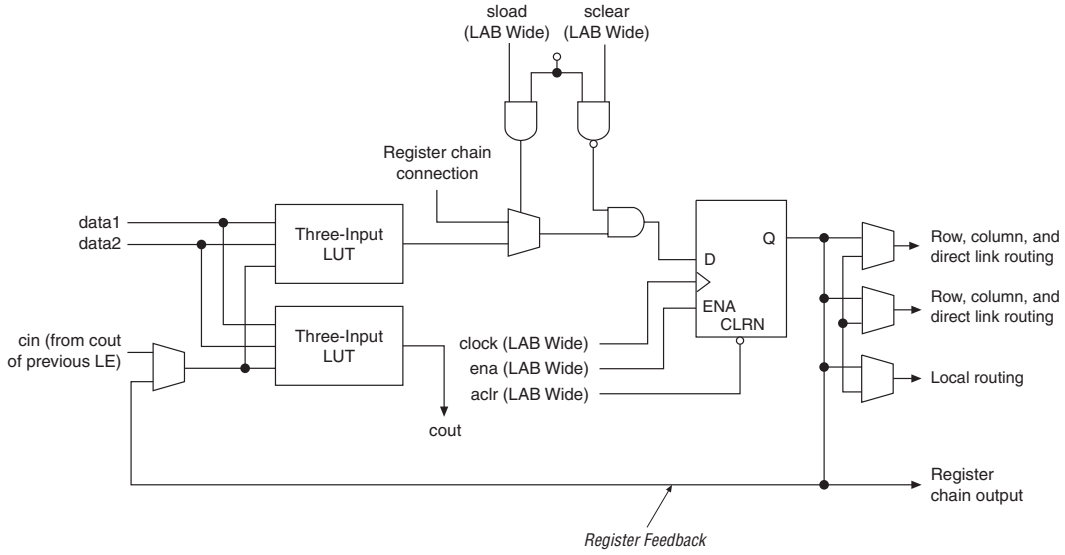
Chapter 12. Embedded Multipliers in Cyclone II Devices
Revised: *February 2007*
Part number: *CII51012-1.2*

Chapter 13. Configuring Cyclone II Devices
Revised: *February 2007*
Part number: *CII51013-3.1*

Chapter 14. IEEE 1149.1 (JTAG) Boundary-Scan Testing for Cyclone II Devices
Revised: *February 2007*
Part number: *CII51014-2.1*

Chapter 15. Package Information for Cyclone II Devices
Revised: *February 2007*
Part number: *CII51015-2.3*

Figure 2–4. LE in Arithmetic Mode



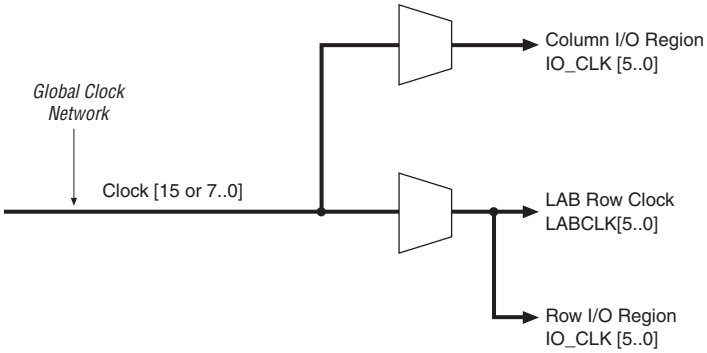
The Quartus II Compiler automatically creates carry chain logic during design processing, or you can create it manually during design entry. Parameterized functions such as LPM functions automatically take advantage of carry chains for the appropriate functions.

The Quartus II Compiler creates carry chains longer than 16 LEs by automatically linking LABs in the same column. For enhanced fitting, a long carry chain runs vertically, which allows fast horizontal connections to M4K memory blocks or embedded multipliers through direct link interconnects. For example, if a design has a long carry chain in a LAB column next to a column of M4K memory blocks, any LE output can feed an adjacent M4K memory block through the direct link interconnect. Whereas if the carry chains ran horizontally, any LAB not next to the column of M4K memory blocks would use other row or column interconnects to drive a M4K memory block. A carry chain continues as far as a full column.

Global Clock Network Distribution

Cyclone II devices contains 16 global clock networks. The device uses multiplexers with these clocks to form six-bit buses to drive column IOE clocks, LAB row clocks, or row IOE clocks (see Figure 2–14). Another multiplexer at the LAB level selects two of the six LAB row clocks to feed the LE registers within the LAB.

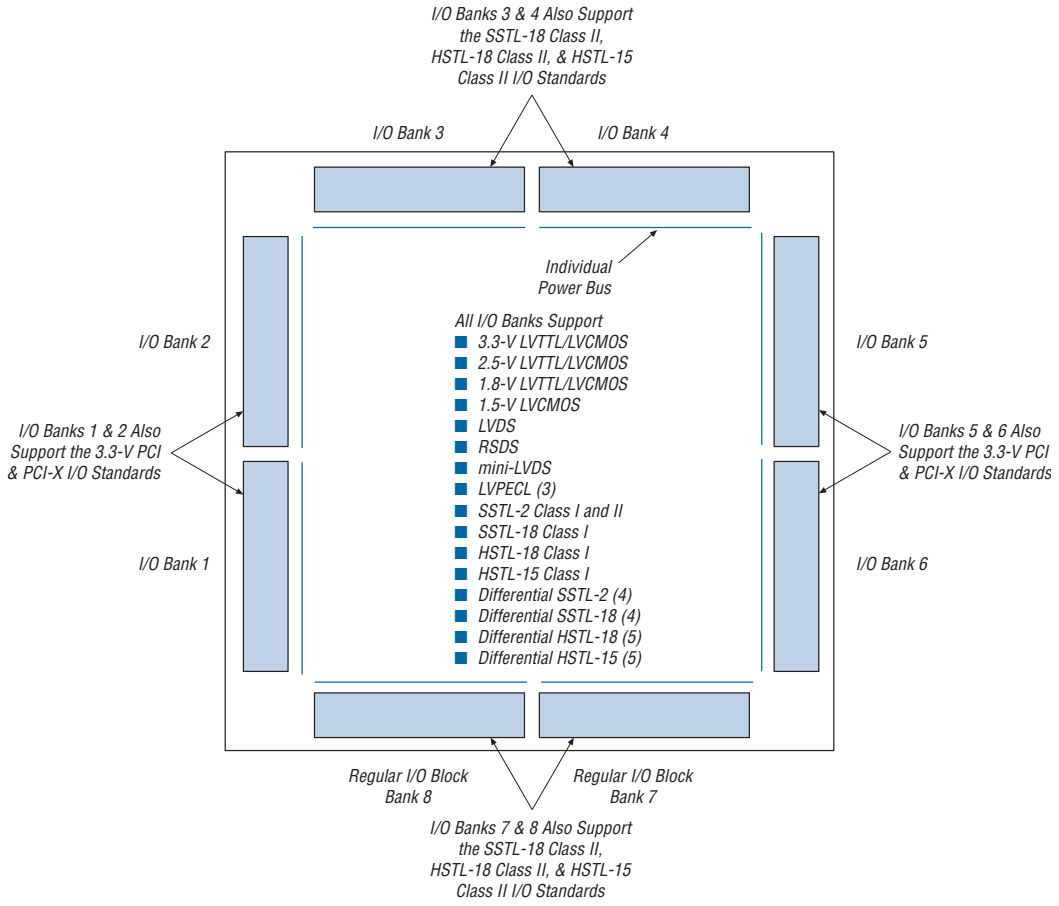
Figure 2–14. Global Clock Network Multiplexers



LAB row clocks can feed LEs, M4K memory blocks, and embedded multipliers. The LAB row clocks also extend to the row I/O clock regions.

IOE clocks are associated with row or column block regions. Only six global clock resources feed to these row and column regions. Figure 2–15 shows the I/O clock regions.

Figure 2–29. EP2C15, EP2C20, EP2C35, EP2C50 & EP2C70 I/O Banks *Notes (1), (2)*



Notes to Figure 2–29:

(1) This is a top view of the silicon die.
(2) This is a graphic representation only. Refer to the pin list and the Quartus II software for exact pin locations.
(3) The LVPECL I/O standard is only supported on clock input pins. This I/O standard is not supported on output pins.
(4) The differential SSTL-18 and SSTL-2 I/O standards are only supported on clock input pins and PLL output clock pins.
(5) The differential 1.8-V and 1.5-V HSTL I/O standards are only supported on clock input pins and PLL output clock pins.

Each I/O bank has its own VCCIO pins. A single device can support 1.5-V, 1.8-V, 2.5-V, and 3.3-V interfaces; each individual bank can support a different standard with different I/O voltages. Each bank also has dual-purpose VREF pins to support any one of the voltage-referenced

Table 5–13 shows the Cyclone II device pin capacitance for different I/O pin types.

Table 5–13. Device Capacitance *Note (1)*

Symbol	Parameter	Typical	Unit
C_{IO}	Input capacitance for user I/O pin.	6	pF
C_{LVDS}	Input capacitance for dual-purpose LVDS/user I/O pin.	6	pF
C_{VREF}	Input capacitance for dual-purpose VREF pin when used as VREF or user I/O pin.	21	pF
C_{CLK}	Input capacitance for clock pin.	5	pF

Note to Table 5–13:

(1) Capacitance is sample-tested only. Capacitance is measured using time-domain reflectometry (TDR). Measurement accuracy is within ±0.5 pF.

Power Consumption

You can calculate the power usage for your design using the PowerPlay Early Power Estimator and the PowerPlay Power Analyzer feature in the Quartus® II software.

The interactive PowerPlay Early Power Estimator is typically used during the early stages of FPGA design, prior to finalizing the project, to get a magnitude estimate of the device power. The Quartus II software PowerPlay Power Analyzer feature is typically used during the later stages of FPGA design. The PowerPlay Power Analyzer also allows you to apply test vectors against your design for more accurate power consumption modeling.

In both cases, only use these calculations as an estimation of power, not as a specification. For more information on PowerPlay tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *Power Estimation and Analysis* section in volume 3 of the *Quartus II Handbook*.

You can obtain the Excel-based PowerPlay Early Power Estimator at www.altera.com. Refer to Table 5–3 on page 5–3 for typical I_{CC} standby specifications.

The power-up current required by Cyclone II devices does not exceed the maximum static current. The rate at which the current increases is a function of the system power supply. The exact amount of current consumed varies according to the process, temperature, and power ramp rate. The duration of the I_{CCINT} power-up requirement depends on the V_{CCINT} voltage supply rise time.

Table 5–16. LE_FF Internal Timing Microparameters (Part 2 of 2)

Parameter	–6 Speed Grade (1)		–7 Speed Grade (2)		–8 Speed Grade (3)		Unit
	Min	Max	Min	Max	Min	Max	
TPRE	191	—	244	—	244	—	ps
	—	—	217	—	244	—	ps
TCLKL	1000	—	1242	—	1242	—	ps
	—	—	1111	—	1242	—	ps
TCLKH	1000	—	1242	—	1242	—	ps
	—	—	1111	—	1242	—	ps
tLUT	180	438	172	545	172	651	ps
	—	—	180	—	180	—	ps

Notes to Table 5–16:

(1) For the –6 speed grades, the minimum timing is for the commercial temperature grade. The –7 speed grade devices offer the automotive temperature grade. The –8 speed grade devices offer the industrial temperature grade.

(2) For each parameter of the –7 speed grade columns, the value in the first row represents the minimum timing parameter for automotive devices. The second row represents the minimum timing parameter for commercial devices.

(3) For each parameter of the –8 speed grade columns, the value in the first row represents the minimum timing parameter for industrial devices. The second row represents the minimum timing parameter for commercial devices.

Table 5–17. IOE Internal Timing Microparameters (Part 1 of 2)

Parameter	–6 Speed Grade (1)		–7 Speed Grade (2)		–8 Speed Grade (3)		Unit
	Min	Max	Min	Max	Min	Max	
TSU	76	—	101	—	101	—	ps
	—	—	89	—	101	—	ps
TH	88	—	106	—	106	—	ps
	—	—	97	—	106	—	ps
TCO	99	155	95	171	95	187	ps
	—	—	99	—	99	—	ps
TPIN2COMBOUT_R	384	762	366	784	366	855	ps
	—	—	384	—	384	—	ps
TPIN2COMBOUT_C	385	760	367	783	367	854	ps
	—	—	385	—	385	—	ps
TCOMBIN2PIN_R	1344	2490	1280	2689	1280	2887	ps
	—	—	1344	—	1344	—	ps

Tables 5–50 and 5–51 show the LVDS timing budget for Cyclone II devices. Cyclone II devices support LVDS receivers at data rates up to 805 Mbps, and LVDS transmitters at data rates up to 640 Mbps.

Table 5–50. LVDS Transmitter Timing Specification (Part 1 of 2)

Symbol	Conditions	–6 Speed Grade				–7 Speed Grade				–8 Speed Grade				Unit
		Min	Typ	Max (1)	Max (2)	Min	Typ	Max (1)	Max (2)	Min	Typ	Max (1)	Max (2)	
f_{HSCLK} (input clock frequency)	×10	10	—	320	320	10	—	275	320	10	—	155.5 (4)	320 (6)	MHz
	×8	10	—	320	320	10	—	275	320	10	—	155.5 (4)	320 (6)	MHz
	×7	10	—	320	320	10	—	275	320	10	—	155.5 (4)	320 (6)	MHz
	×4	10	—	320	320	10	—	275	320	10	—	155.5 (4)	320 (6)	MHz
	×2	10	—	320	320	10	—	275	320	10	—	155.5 (4)	320 (6)	MHz
	×1	10	—	402.5	402.5	10	—	402.5	402.5	10	—	402.5 (8)	402.5 (8)	MHz
HSIODR	×10	100	—	640	640	100	—	550	640	100	—	311 (5)	550 (7)	Mbps
	×8	80	—	640	640	80	—	550	640	80	—	311 (5)	550 (7)	Mbps
	×7	70	—	640	640	70	—	550	640	70	—	311 (5)	550 (7)	Mbps
	×4	40	—	640	640	40	—	550	640	40	—	311 (5)	550 (7)	Mbps
	×2	20	—	640	640	20	—	550	640	20	—	311 (5)	550 (7)	Mbps
	×1	10	—	402.5	402.5	10	—	402.5	402.5	10	—	402.5 (9)	402.5 (9)	Mbps
t_{DUTY}	—	45	—	55	—	45	—	55	—	45	—	55	—	%
	—	—	—	—	160	—	—	—	312.5	—	—	—	363.6	ps
TCCS (3)	—	—	—	200		—	—	200		—	—	200		ps
Output jitter (peak to peak)	—	—	—	500		—	—	500		—	—	550 (10)		ps
t_{RISE}	20–80%	150	200	250		150	200	250		150	200	250 (11)		ps

VCCA & GNDA

Each Cyclone II PLL uses separate VCC and ground pin pairs for their analog circuitry. The analog circuit power and ground pin for each PLL is called VCCA_PLL<*PLL number*> and GNDA_ PLL<*PLL number*>. Connect the VCCA power pin to a 1.2-V power supply, even if you do not use the PLL. Isolate the power connected to VCCA from the power to the rest of the Cyclone II device or any other digital device on the board. You can use one of three different methods of isolating the VCCA pin:

- Use separate VCCA power planes
- Use a partitioned VCCA island within the VCCINT plane
- Use thick VCCA traces

Separate VCCA Power Plane

A mixed signal system is already partitioned into analog and digital sections, each with its own power planes on the board. To isolate the VCCA pin using a separate VCCA power plane, connect the VCCA pin to the analog 1.2-V power plane.

Partitioned VCCA Island Within the VCCINT Plane

Fully digital systems do not have a separate analog power plane on the board. Since it is expensive to add new planes to the board, you can create islands for VCCA_PLL. Figure 7–16 shows an example board layout with an analog power island. The dielectric boundary that creates the island should be 25 mils thick. Figure 7–16 shows a partitioned plane within V_{CCINT} for VCCA.

Figure 10–13. 1.5-V HSTL Class I Termination

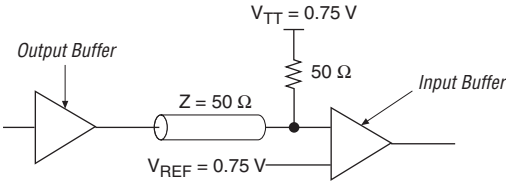
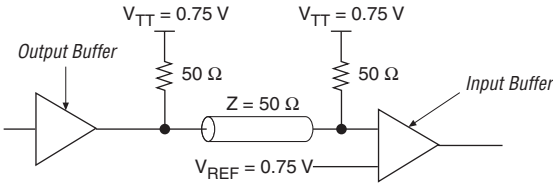


Figure 10–14. 1.5-V HSTL Class II Termination



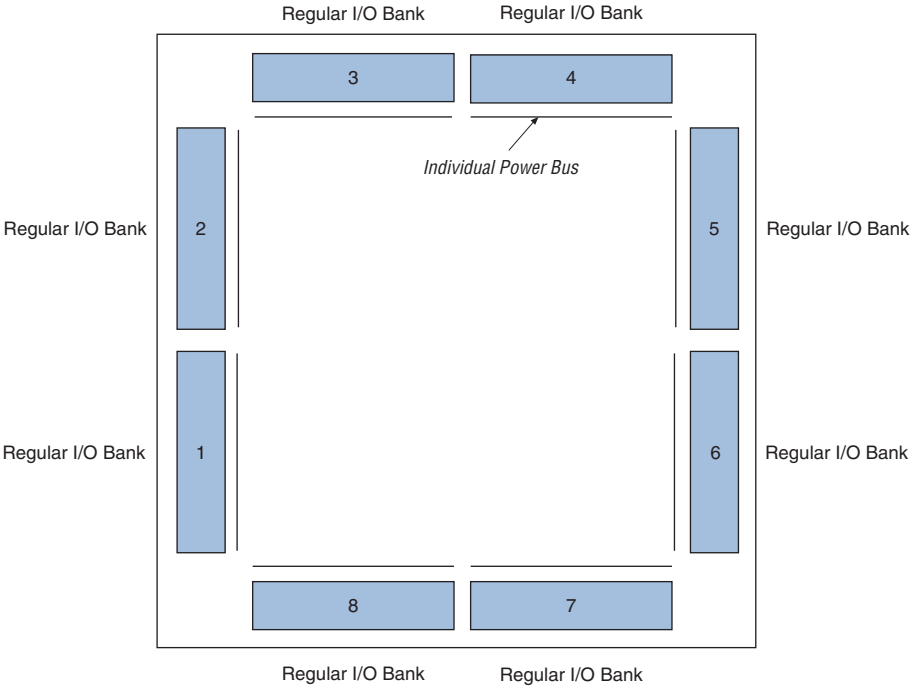
1.5-V Pseudo-Differential HSTL Class I and II

The 1.5-V differential HSTL standard is formulated under EIA/JEDEC Standard, EIA/JESD8-6: A 1.5V Output Buffer Supply Voltage Based Interface Standard for Digital Integrated Circuits.

The 1.5-V differential HSTL specification is the same as the 1.5-V single-ended HSTL specification. It is used for applications designed to operate in the 0.0- to 1.5-V HSTL logic switching range, such as QDR memory clock interfaces. Cyclone II devices support both input and output levels. Refer to Figures 10–15 and 10–16 for details on the 1.5-V differential HSTL termination.

Cyclone II devices do not support true 1.5-V differential HSTL standards. Cyclone II devices support pseudo-differential HSTL outputs for `PLL_OUT` pins and pseudo-differential HSTL inputs for clock pins. Pseudo-differential inputs require an input reference voltage as opposed to the true differential inputs. Refer to Table 10–1 on page 10–2 for information about pseudo-differential HSTL.

Figure 10–20. EP2C15, EP2C20, EP2C35, EP2C50, and EP2C70 Device I/O Banks *Notes (1), (2)*



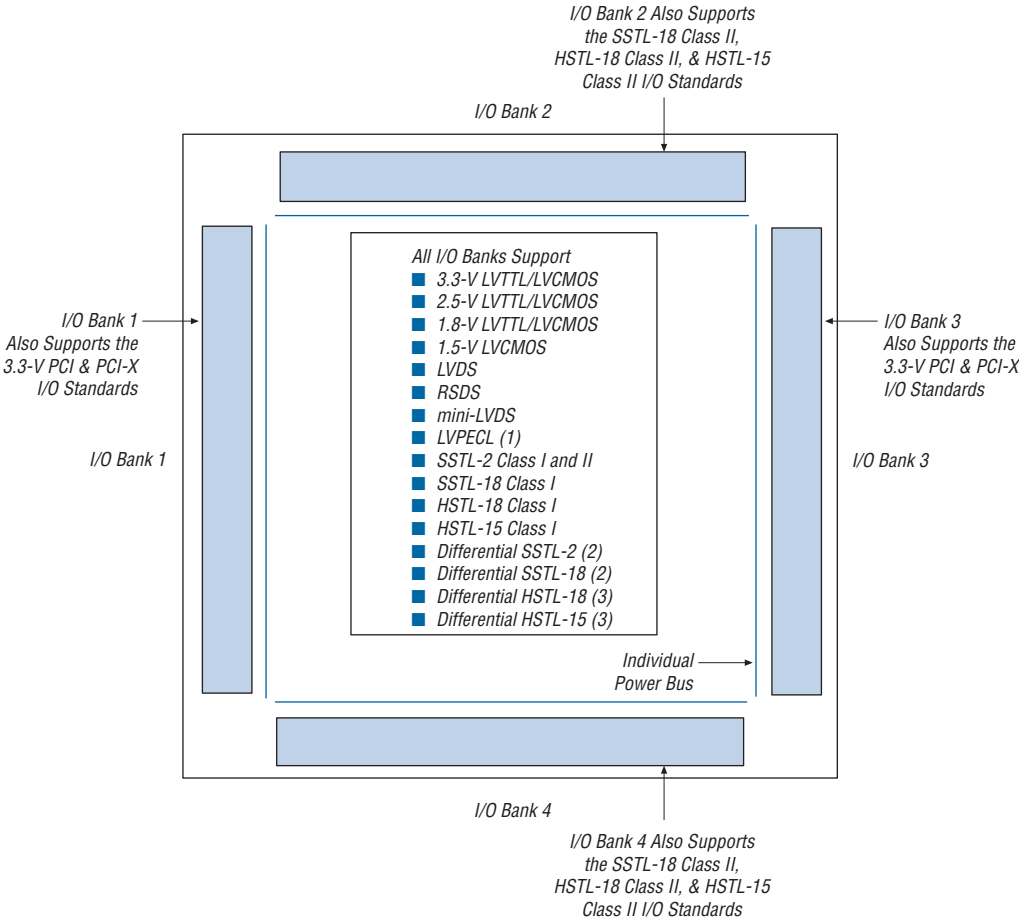
Notes to Figure 10–20:

(1) This is a top view of the silicon die.

(2) This is a graphic representation only. Refer to the pin list and the Quartus II software for exact pin locations.

pins in each I/O bank (on both rows and columns) support the high-speed I/O interface. Cyclone II pin tables list the pins that support the high-speed I/O interface.

Figure 11–1. I/O Banks in EP2C5 & EP2C8 Devices



Notes to Figure 11–1:

(1) The LVPECL I/O standard is only supported on clock input pins. This I/O standard is not supported on output pins.

(2) The differential SSTL-18 and SSTL-2 I/O standards are only supported on clock input pins and PLL output clock pins.

(3) The differential 1.8-V and 1.5-V HSTL I/O standards are only supported on clock input pins and PLL output clock pins.

All information in the "Single Device PS Configuration Using a MAX II Device as an External Host" on page 13–22 section is also applicable when using a microprocessor as an external host. Refer to that section for all configuration information.

The MicroBlaster™ software driver allows you to configure Altera FPGAs, including Cyclone II devices, through the ByteBlaster II or ByteBlasterMV cable in PS mode. The MicroBlaster software driver supports a RBF programming input file and is targeted for embedded PS configuration. The source code is developed for the Windows NT operating system, although you can customize it to run on other operating systems.

Since the Cyclone II device can decompress the compressed configuration data on-the-fly during PS configuration, the MicroBlaster software can accept a compressed RBF file as its input file.

For more information on the MicroBlaster software driver, see the *Configuring the MicroBlaster Passive Serial Software Driver White Paper* and source files on the Altera web site at **www.altera.com**.

If you turn on the **Enable user-supplied start-up clock (CLKUSR)** option in the Quartus II software, the Cyclone II devices does not enter user mode after the MicroBlaster has transmitted all the configuration data in the RBF file. You need to supply enough initialization clock cycles to `CLKUSR` pin to enter user mode.

Single Device PS Configuration Using a Configuration Device

You can use an Altera configuration device (for example, an EPC2, EPC1, or enhanced configuration device) to configure Cyclone II devices using a serial configuration bitstream. Configuration data is stored in the configuration device. Figure 13–13 shows the configuration interface connections between the Cyclone II device and a configuration device.

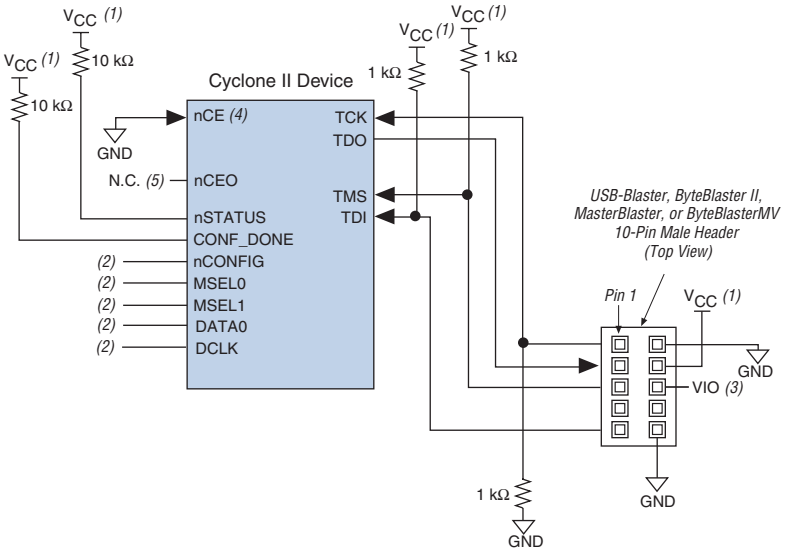
The figures in this chapter only show the configuration-related pins and the configuration pin connections between the configuration device and the FPGA.

For more information on enhanced configuration devices and flash interface pins (e.g., `PGM[2..0]`, `EXCLK`, `PORSEL`, `A[20..0]`, and `DQ[15..0]`), see the *Enhanced Configuration Devices (EPC4, EPC8 & EPC16) Data Sheet*.

Single Device JTAG Configuration

During JTAG configuration, you can use the USB-Blaster, MasterBlaster, ByteBlaster II, or ByteBlasterMV download cable to download data to the device. Configuring Cyclone II devices through a cable is similar to programming devices in system. Figure 13–22 shows JTAG configuration of a single Cyclone II device using a download cable.

Figure 13–22. JTAG Configuration of a Single Device Using a Download Cable



Notes to Figure 13–22:

(1) The pull-up resistor should be connected to the same supply voltage as the USB-Blaster, MasterBlaster (VIO pin), ByteBlaster II, or ByteBlasterMV cable.

(2) Connect the nCONFIG and MSEL[1..0] pins to support a non-JTAG configuration scheme. If only JTAG configuration is used, connect the nCONFIG pin to V_{CC}, and the MSEL[1..0] pins to ground. In addition, pull DCLK and DATA0 to either high or low, whichever is convenient on your board.

(3) Pin 6 of the header is a V_{IO} reference voltage for the MasterBlaster output driver. V_{IO} should match the device's V_{CCIO}. Refer to the *MasterBlaster Serial/USB Communications Cable Data Sheet* for this value. In the ByteBlasterMV, this pin is a no connect. In the USB-Blaster and ByteBlaster II, this pin is connected to nCE when it is used for AS programming, otherwise it is a no connect.

(4) nCE must be connected to GND or driven low for successful JTAG configuration.

(5) The nCEO pin can be left unconnected or used as a user I/O pin when it does not feed other device's nCE pin.

To configure a single device in a JTAG chain, the programming software places all other devices in BYPASS mode. In BYPASS mode, Cyclone II devices pass programming data from the TDI pin to the TDO pin through a single bypass register without being affected internally. This scheme

14. IEEE 1149.1 (JTAG) Boundary-Scan Testing for Cyclone II Devices

CII51014-2.1

Introduction

As printed circuit boards (PCBs) become more complex, the need for thorough testing becomes increasingly important. Advances in surface-mount packaging and PCB manufacturing have resulted in smaller boards, making traditional test methods (e.g., external test probes and "bed-of-nails" test fixtures) harder to implement. As a result, cost savings from PCB space reductions are sometimes offset by cost increases in traditional testing methods.

In the 1980s, the Joint Test Action Group (JTAG) developed a specification for boundary-scan testing that was later standardized as the IEEE Std. 1149.1 specification. This boundary-scan test (BST) architecture offers the capability to efficiently test components on PCBs with tight lead spacing.

This BST architecture tests pin connections without using physical test probes and captures functional data while a device is operating normally. Boundary-scan cells in a device force signals onto pins or capture data from pin or logic array signals. Forced test data is serially shifted into the boundary-scan cells. Captured data is serially shifted out and externally compared with expected results. Figure 14–1 shows the concept of boundary-scan testing.

Figure 14–1. IEEE Std. 1149.1 Boundary-Scan Testing

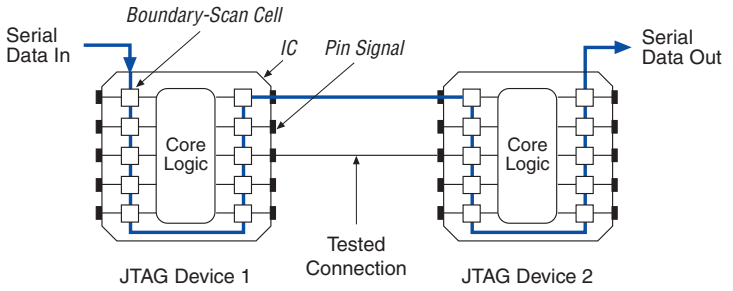
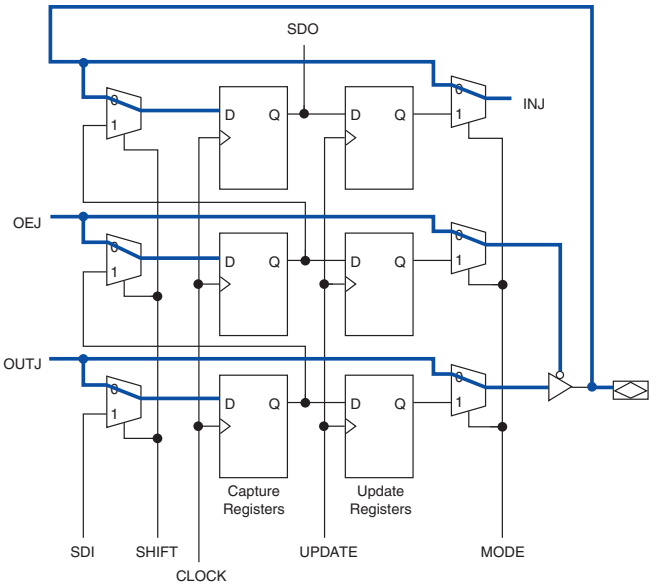


Figure 14–8. IEEE Std. 1149.1 BST SAMPLE/PRELOAD Mode

Capture Phase

In the capture phase, the signals at the pin, OEJ and OUTJ, are loaded into the capture registers. The CLOCK signals are supplied by the TAP controller's CLOCKDR output. The data retained in these registers consists of signals from normal device operation.



Shift & Update Phases

In the shift phase, the previously captured signals at the pin, OEJ and OUTJ, are shifted out of the boundary-scan register via the TDO pin using CLOCK. As data is shifted out, the patterns for the next test can be shifted in via the TDI pin.

In the update phase, data is transferred from the capture to the UPDATE registers using the UPDATE clock. The data stored in the UPDATE registers can be used for the EXTEST instruction.

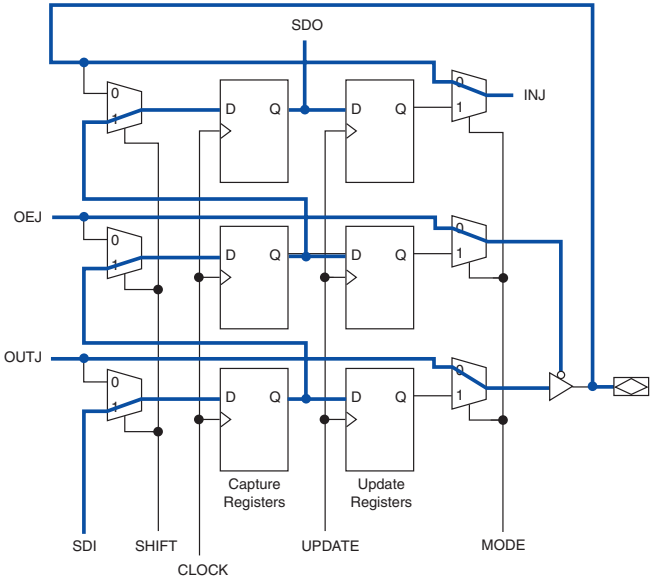
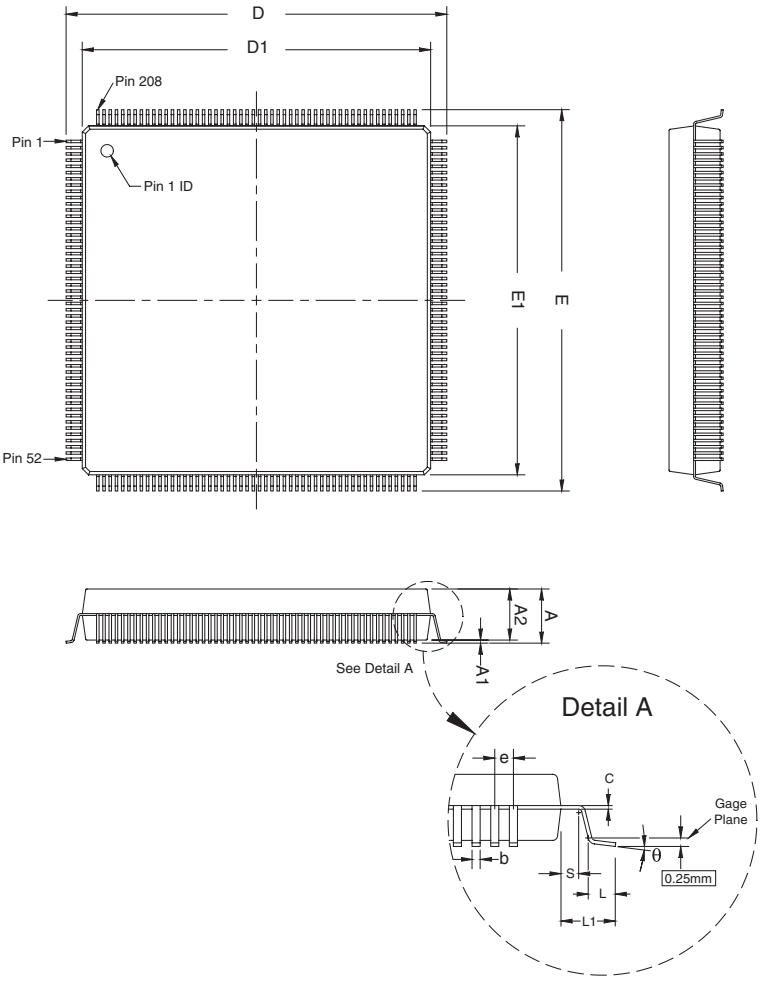


Table 15–8. 208-Pin PQFP Package Outline Dimensions (Part 2 of 2)			
Symbol	Millimeter		
	Min.	Nom.	Max.
e	0.50 BSC		
q	0°	3.5°	8°

Figure 15–2 shows a 208-pin PQFP package outline.

Figure 15–2. 208-pin PQFP Package Outline



Document Revision History

Table 15–21 shows the revision history for this document.

Table 15–21. Document Revision History

Date & Document Version	Changes Made	Summary of Changes
February 2007 v2.3	Added document revision history.	
November 2005 v2.1	Updated information throughout.	
July 2005 v2.0	Updated packaging information.	
November 2004 v1.0	Added document to the Cyclone II Device Handbook.	